

UNITED STATES PATENT AND TRADEMARK OFFICE

APPLICANT(S)	<i>Dimitry Shur</i>	GROUP ART UNIT:	2881
APPLN. NO.:	10/691,746	EXAMINER:	Johnston, Phillip A.
FILED:	10/22/2003		
TITLE:	SYSTEM AND METHOD FOR MEASURING OVERLAY ERRORS		

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Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Sir:

This paper is responsive to the Office Action dated July 31<sup>st</sup> 2006, having a shortened statutory period of three months expiring October 31<sup>st</sup> 2006 Further examination and reconsideration are respectfully requested.

FEES

No additional fees are believed to be owed in connection with this response.